

Notice of References Cited

Application/Control No.

10/621,772

Applicant(s)/Patent Under
Reexamination
O'BRIEN, WAYNE PATRICK

Examiner

ZHENG WEI

Art Unit

2192

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,159,687 A	10-1992	Richburg, Joseph B.	717/106
*	B	US-5,442,792 A	08-1995	Chun, Robert K.	717/155
*	C	US-5,768,590 A	06-1998	Kimura et al.	717/106
*	D	US-5,815,717 A	09-1998	Stack, Brian T.	717/105
*	E	US-6,212,672 B1	04-2001	Keller et al.	717/104
*	F	US-6,408,431 B1	06-2002	Heughebaert et al.	717/106
*	G	US-2002/0095654 A1	07-2002	Fukase et al.	717/106
*	H	US-2002/0129331 A1	09-2002	Zhang et al.	717/106
*	I	US-2003/0110468 A1	06-2003	Maki, Yoshiyuki	717/106
*	J	US-2004/0015832 A1	01-2004	Stapp et al.	717/106
*	K	US-2004/0034846 A1	02-2004	Ortal et al.	717/111
*	L	US-2004/0064804 A1	04-2004	Daniels et al.	717/106
*	M	US-6,748,588 B1	06-2004	Fraser et al.	717/146

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0111702 A1	06-2004	Chan, Kin Ming	717/113
*	B	US-6,889,373 B2	05-2005	Fukase et al.	717/106
*	C	US-6,973,640 B2	12-2005	Little et al.	717/106
*	D	US-7,017,146 B2	03-2006	Dellarocas et al.	717/106
*	E	US-7,032,210 B2	04-2006	Alloing et al.	717/106
*	F	US-7,047,518 B2	05-2006	Little et al.	717/108
*	G	US-2006/0294500 A1	12-2006	Chiang, Hiang-Swee	717/109
*	H	US-7,171,646 B2	01-2007	Charisius et al.	717/100
*	I	US-7,305,656 B2	12-2007	Fish et al.	717/105
*	J	US-2008/0229278 A1	09-2008	Liu et al.	717/106
*	K	US-7,463,263 B2	12-2008	Gilboa, Yuval	345/440
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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